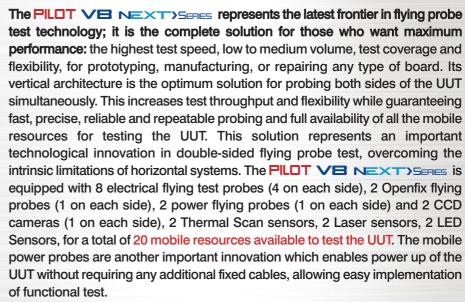


FLYING PROBE SYSTEM

PILOT VB NEXT > SERIES

PILOT NEXT > SERIES LINE

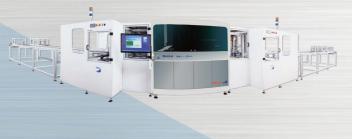






The test tools and techniques of the PILOT VE NEXT>SERIES include:

- FNODE signature analysis on the nets of the UUT
- Standard analog and digital in-circuit test
- Vectorless tests (AUTIC and OPENFIX), to test ICs for opens and shorts
- PWMON digital net analysis
- Continuity test to detect open tracks on the PCB
- Visual tests for component presence/absence and rotation
- Optional functional test and boundary scan test capabilities
- · On Board Programming tools for digital devices
- Optional Thermal Scan Resources
- ALI: Automatic Laser Inspection for presence/absence and warpage compensation
- · LED Sensor for light intensity and colour recognition



All of these measurement capabilities and techniques can be combined in a single test program. Important innovations, such as the net-oriented, FNODE and PWMON measurement techniques, provide high fault coverage with significant savings in terms of programming and test time. In addition, with its full complement of test resources, the PILOT VEINEXTOSERIES can utilize the test programs developed on any other Seica flying probe system, since it has the capability to operate in all prober configurations (2 or 4 probes on a single side or on both sides).

VIP PLATFORM

The PILOT VE NEXT>SERIES is based on the Seica VIP platform, which includes the innovative VIVA software. Test program development is organized in 3 simple steps: "Prepare", "Verify" and "Test", where the user is guided through a series of automated operations in an intuitive, self-explanatory environment, drastically reducing programming time and minimizing errors and omissions, ensuring the quality of the final test program.

TDS Pilot Next> series V8 vers. 01 UK 11/2017

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Seica reserves the right to change the technical specifications without notice

PROBES AND CAMERAS

| THODEO AND CAMEING | |
|--|---------------------|
| Probes Position - Test Side | Front/Rear |
| Maximum Number of Resources | 20 |
| Number of Electrical Probes | 8 (4 front, 4 rear) |
| Number of Openfix Probes | 2 (1 front, 1 rear) |
| Number of Power Probes | 2 (1 front, 1 rear) |
| Number of Fixed Probes / Upgrade Up To | 0/192 |
| Maximum Digital Embedded Channels | 4 |
| Number of CCD Colour Cameras | 2 (1 front, 1 rear) |
| Automatic Marker Recognition | Yes |
| Automatic UUT Planarity Compensation | Yes |
| Thermal Scan Module (option) | 2 (1 front, 1 rear) |
| | |

BOARD CLAMPING SYSTEM, UUT SIZES AND WORK AREA (*)

| Manual (Dual Action) |
|--|
| 538 x 610 mm (21.18 X 24") Manual |
| 518 x 610 mm (20.39 X 24") |
| 540 x 610 mm (21.25 X 24") |
| 520 x 610 mm (20.47 X 24") Auto |
| 20 x 20 mm (0.78 x 0.78") |
| 5 mm (0.19") manual/3mm(0.18") automatic |
| 0.3 mm (0.00118")manual/1mm (0.00393")auto |
| 37 mm (1.456")auto |
| Vertical |
| Front (mm) Back (mm) |
| 40 40 |
| 40 90 |
| 40 300 |
| 90 90 |
| 90 40 |
| 300 40 |
| 2 mm manual/6 mm auto |
| |

PITCH

Minimum Pad Pitch 150 μm (6 mil) Minimum Pad Size 50 μm (2 mil)

PROBE FEATURES

-3.0 mm to 40 mm programmable **Z-axis Travel Contact Force** 5 g - 100 g programmable

TESTS AND MEASUREMENTS (INSTRUMENTS DSP)

| Voltage Generator 1 DC/AC (DRA) | ±1 mV to ±10 V (±0.1%) |
|---|---|
| Voltage Generator 2 DC/AC (DRB) | ±1 mV to ±10 V (±0.1%) |
| Voltage Generator 3 DC/AC (DRC) | ±25 mV to ±100 V (±0.2%) |
| Current Generator DC/AC | ±1 nA to ±0.5 A (±0.1%) |
| Waveform Generator 1 Sin, Tri, Arbitrary (D | (RA) 1 Hz to 3 MHz $(\pm 1 \text{ mHz}) - \pm 10 \text{ V max}$ |
| Waveform Generator 2 Sin, Tri, Arbitrary (D | RC) 1 Hz to 10 KHz (±10 mHz) - ±100 Vmax |
| Voltage Measurements DC/AC | ±200 μV to ±100 V |
| Current Measurements DC/AC | ±3 nA to ±0.5 A |
| Frequency Measurement | 0.1 Hz to 50 MHz |
| Digital Embedded Channel | ±12 V - 500 mA - 10 MHz |
| Resistance Measurement | 1 mΩ to 100 MΩ |
| Capacitance Measurement | 1 pF to 1 F |
| Inductor Measurement | 1 µH to 1 H |
| Zener Measurement | up to 100 V (200V option) |
| Automatic Visual Inspection | Yes |
| | |

GENERAL REQUIREMENTS

| Temperature Range | | 25°C ± 10°C | |
|-------------------|---------------------|-------------------|---------------------------|
| Humidity | | 30 - 80 % | |
| | System | Loader | |
| Power | 220 V/50 Hz 12 A, | 220 V/50 Hz 2 A | |
| | 110 V/60 Hz 24 A | | |
| Power Consumption | 3.5 kW max | 1.0 kW max | |
| Air Flow | 0.35 CFM - 10l/min. | 0.3 CFM - 6l/min. | |
| Weight | 1350 kg (2976 lbs) | 200 Kg (441 lbs) | |
| Length | 175 cm (68.9") | 206 cm (81.10") | |
| Width | 123 cm (48.4") | 155 cm (61,02") | |
| Height | 174 cm (68.50") | 174 cm (68.50") | (214 cm with light-tower) |

SOFTWARE FEATURES

| GOI I WAILE I LATOILE | |
|----------------------------|------------|
| PC/Operating System | Windows 7 |
| Software | VIVA |
| Automatic Test Generation | Yes |
| Autodebug | Yes |
| Data Input Format | CAD Data/M |
| Parallel Test Capabilities | Yes |
| | |

*Universal carrier for unique board configurations.

